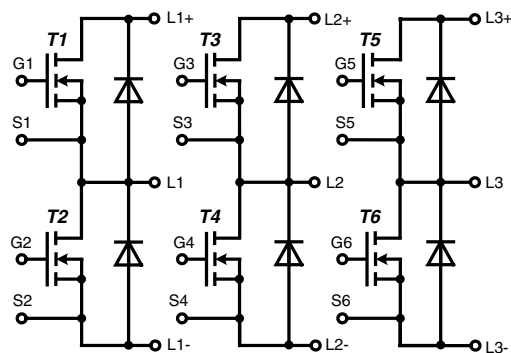
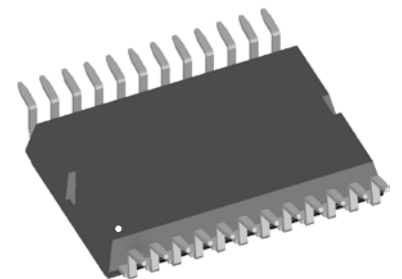


Three phase full Bridge
with Trench MOSFETs
in DCB isolated high current package

$V_{DSS} = 75\text{ V}$
 $I_{D25} = 255\text{ A}$
 $R_{DSon\ typ.} = 1.1\text{ m}\Omega$

Part number
MTI200WX75GD



Features / Advantages:

- MOSFETs in trench technology:
 - low R_{DSon}
 - optimized intrinsic reverse diode
- package:
 - high level of integration
 - high current capability
 - aux. terminals for MOSFET gate control
 - terminals for soldering or welding connections
 - isolated DCB ceramic base plate with optimized heat transfer
- Space and weight savings
- High current capability

Applications:

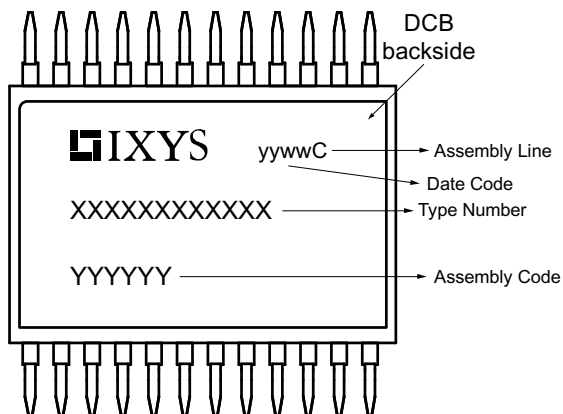
- AC drives
- in automobiles
 - electric power steering
 - starter generator
 - in industrial vehicles
 - propulsion drives
 - fork lift drives
 - Battery supplied equipment
 - DC-DC converter

Package: ISOPLUS-DIL®

- High level of integration
- RoHS compliant
- Terminals for soldering or welding connections
- Space and weight savings
- High reliability
- Low thermal impedance

MOSFETs				Ratings		
Symbol	Definitions	Conditions	min.	typ.	max.	Unit
V_{DSS}	drain source breakdown voltage	$T_{VJ} = 25^{\circ}\text{C to } 150^{\circ}\text{C}$			75	V
V_{GS}	max. DC gate source voltage				± 15	V
V_{GSM}	max. transient gate source voltage				± 20	V
I_{D25}	continuous drain current	$T_C = 25^{\circ}\text{C}$			255	A
I_{D90}	(die capability)	$T_C = 90^{\circ}\text{C}$			190	A
$R_{DS(on)}^{1)}$	static drain source on resistance	on chip level at $I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}$		1.1 1.8	1.3	m Ω m Ω
$V_{GS(th)}$	gate threshold voltage	$I_D = 275 \mu\text{A}; V_{DS} = V_{GS}$	2.3	3.1	3.8	V
I_{DSS}	drain source leakage current	$V_{DS} = V_{DSS}; V_{GS} = 0 \text{ V}$		10	1 100	μA μA
I_{GSS}	gate source leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$			500	nA
R_G	gate resistance	on chip		2.7		Ω
C_{iss}	input capacitance	} $V_{GS} = 0 \text{ V}; V_{DS} = 38 \text{ V}; f = 1 \text{ Mhz}$		10.8	14.4	nF
C_{oss}	output capacitance		2.42	3.22	nF	
C_{rss}	reverse transfer capacitance		110	-	pF	
Q_g	total gate charge	} $V_{GS} = 10 \text{ V}; V_{DS} = 38 \text{ V}; I_D = 100 \text{ A}$		155		nC
Q_{gs}	gate source charge		53		nC	
Q_{gd}	gate drain (Miller) charge		32		nC	
$t_{d(on)}$	turn-on delay time	} inductive load $V_{GS} = 10 \text{ V}; V_{DS} = 30 \text{ V}$ $I_D = 100 \text{ A}; R_G = 27 \Omega$ $T_{VJ} = 125^{\circ}\text{C}$		145		ns
t_r	current rise time		70		ns	
$t_{d(off)}$	turn-off delay time		520		ns	
t_f	current fall time		55		ns	
E_{on}	turn-on energy per pulse		80		μJ	
E_{off}	turn-off energy per pulse		350		μJ	
$E_{rec(off)}$	turn-off reverse recovery losses	8		μJ		
R_{thJC}	thermal resistance junction to case				0.85	K/W
R_{thJH}	thermal resistance junction to heatsink	with heat transfer paste (IXYS test setup)		1.1	1.4	K/W
		$^{1)} V_{DS} = I_D \cdot (R_{DS(on)} + 2 \cdot R_{Pin \text{ to Chip}})$				
Source-Drain Diode						
I_{F25}	forward current (body diode)	$V_{GS} = 0 \text{ V}$			175	A
I_{F90}					100	A
V_{SD}	source drain voltage	$I_F = 100 \text{ A}; V_{GS} = 0 \text{ V}$		0.9	1.2	V
Q_{RM}	reverse recovery charge	} $V_R = 30 \text{ V}; I_F = 100 \text{ A}$ $R_G = 27 \Omega$		730		nC
I_{RM}	max. reverse recovery current		27		A	
t_{rr}	reverse recovery time		42		ns	

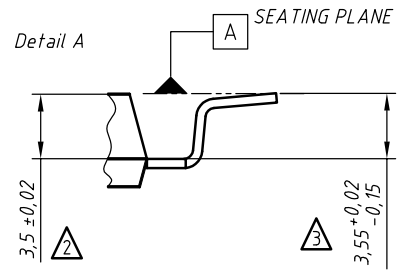
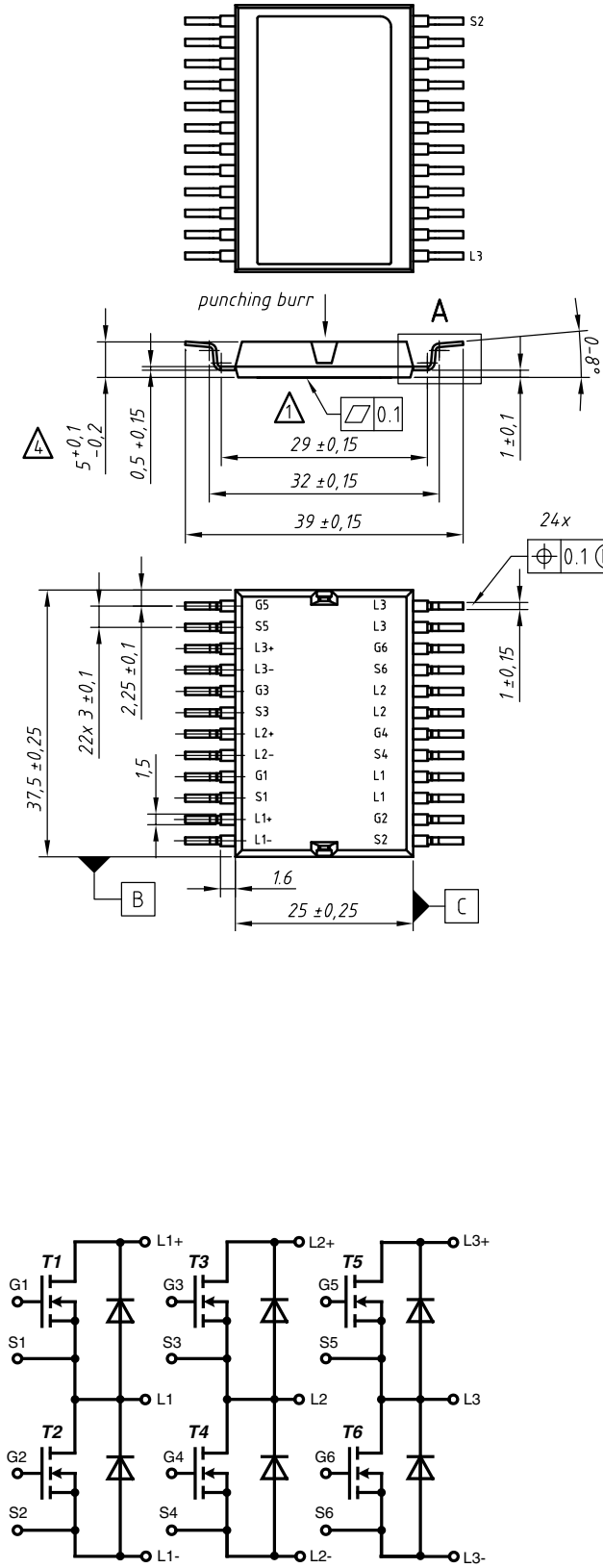
Package ISOPLUS-DIL®				Ratings		
Symbol	Definitions	Conditions	min.	typ.	max.	Unit
I_{RMS}	RMS current	per pin in main current paths (L1+...L3+, L1-...L3-, L1...L3) may be additionally limited by external connections (PCB tracks) 2 pins for output L1, L2, L3			75	A
T_{stg}	storage temperature		-55		125	°C
T_{VJM}	virtual junction temperature		-55		175	°C
Weight				25		g
F_c	mounting force with clip		50		250	N
V_{ISOL}	isolation voltage	$t = 1$ second	50/60 Hz, RMS, $I_{ISOL} \leq 1$ mA	1200		V
		$t = 1$ minute		1000		V
$R_{pin-chip}$	resistance terminal to chip	$V_{DS} = I_D \cdot (R_{DS(on)} + 2 \cdot R_{pin\ to\ chip})$		0.5		mΩ
C_p	coupling capacity	between shorted pins and back side metallization		160		pF


Part number

- M = Module
- T = Trench MOSFET
- I = OPTIMOS
- 200 = Current Rating [A]
- WX = 6-Pack with separated phase legs
- 75 = Reverse Voltage [V]
- GD = ISOPLUS-DIL

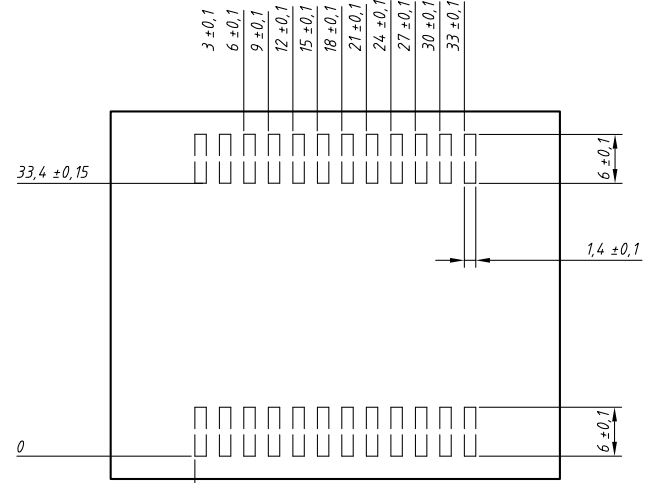
Ordering	Part Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	MTI200WX75GD-SMD	MTI200WX75GD	Blister	28	513668

Outlines ISOPLUS-DIL®



contact pin:
 - galv. tin plating, per pin side: Sn 10...25 µm, undercoating Ni 0,2...1 µm
 - stamping edges may be free of tin
 - punching burr: ≤ 0,05mm

- ① Convex bow of substrate, typ. 10-40 µm longitudinal and 5-15 µm transversal
- ② Distance between pin and case bottom side.
- ③ Distance between pin and contact surface.
- ④ Distance between parallel planes aligned to top and bottom sides of the package



Remarks:

- 1) pin layout / dimensions are conditionally
- 2) soldering paste thickness: 200µm

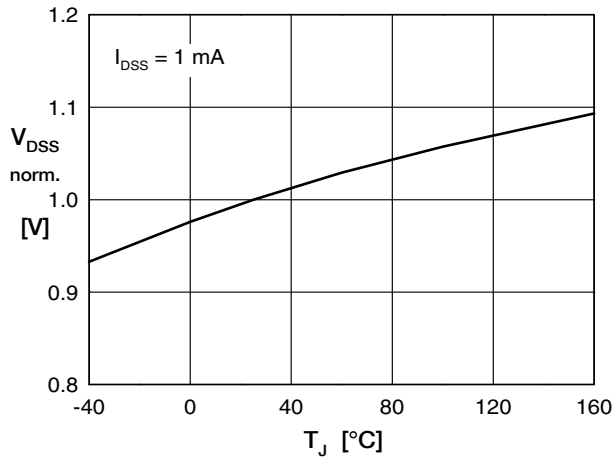


Fig. 1 Drain source breakdown voltage V_{DSS} vs. junction temperature T_{VJ}

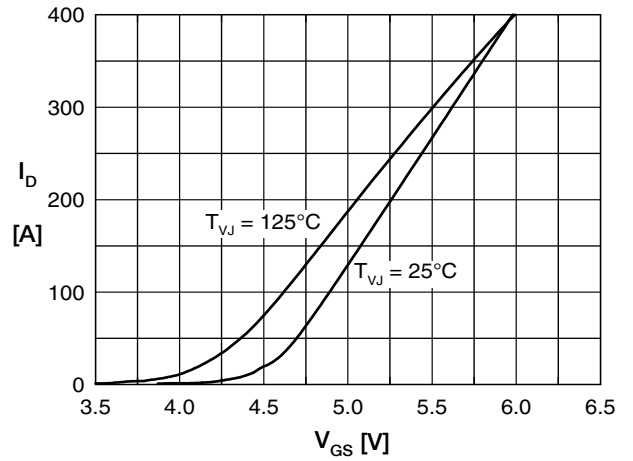


Fig. 2 Typ. transfer characteristics

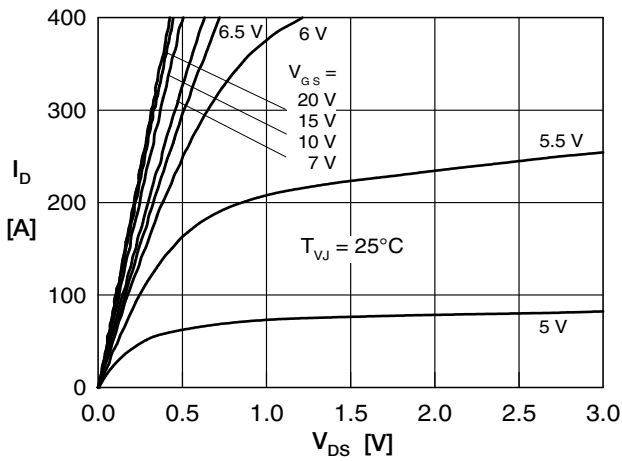


Fig. 3 Typ. output characteristics on die level

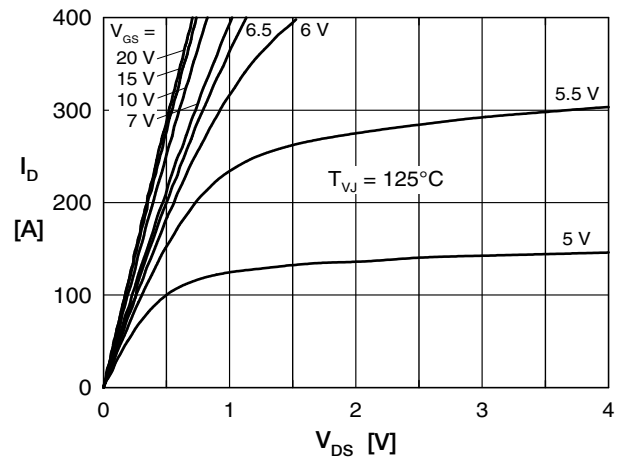


Fig. 4 Typ. output characteristics on die level

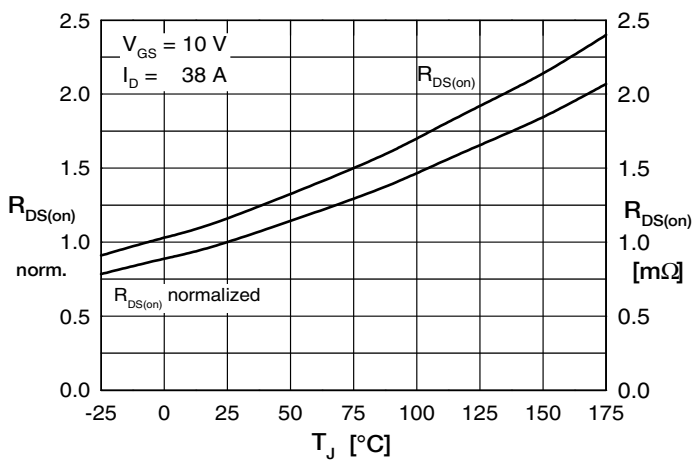


Fig. 5 Drain source on-state resistance $R_{DS(on)}$ vs. junction temperature T_{VJ} , on die level

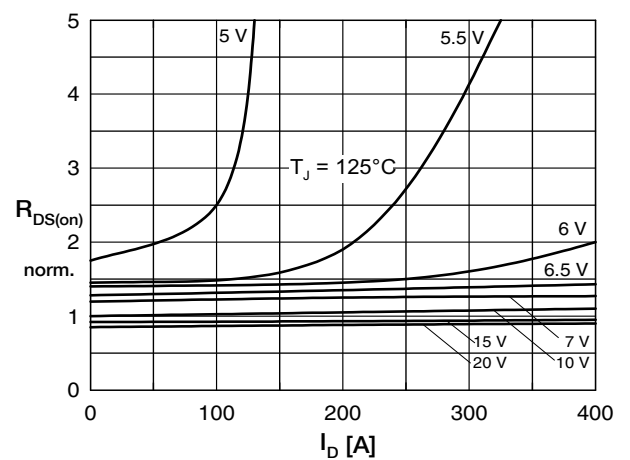


Fig. 6 Drain source on-state resistance $R_{DS(on)}$ versus I_D , on die level

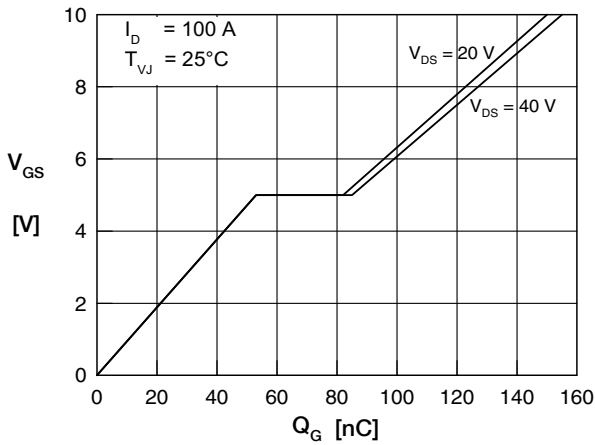


Fig.7 Typical turn on gate charge

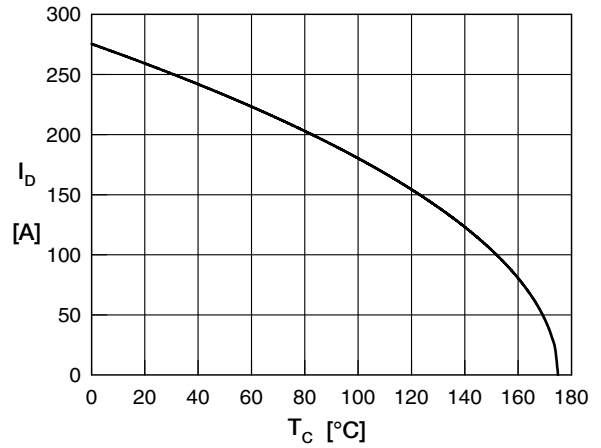
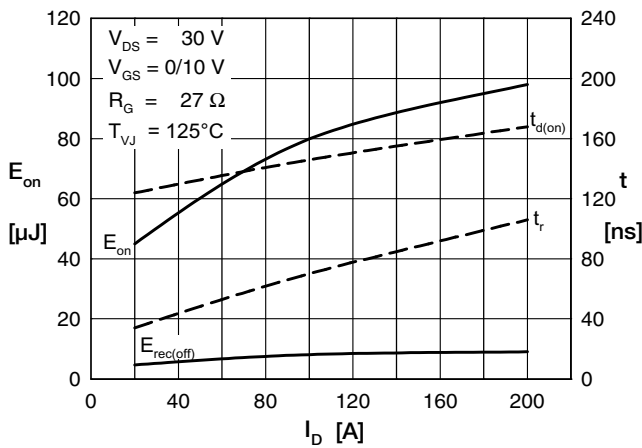

 Fig. 8 Drain current I_D vs. case temperature T_C (Chip capability)


Fig. 9 Typ. turn-on energy and switching times versus drain current, inductive switching

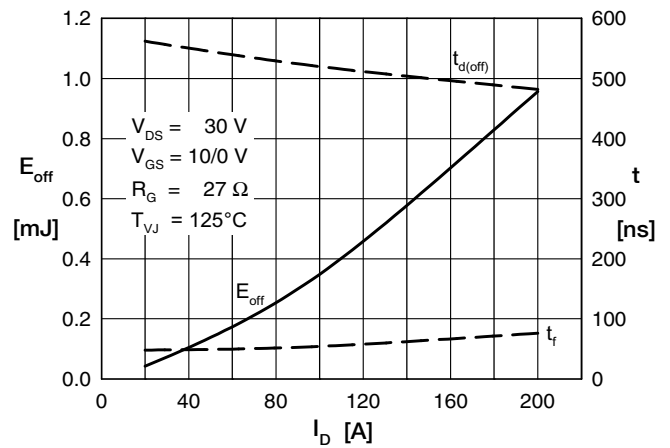


Fig. 10 Typ. turn-off energy and switching times versus drain-current, inductive switching

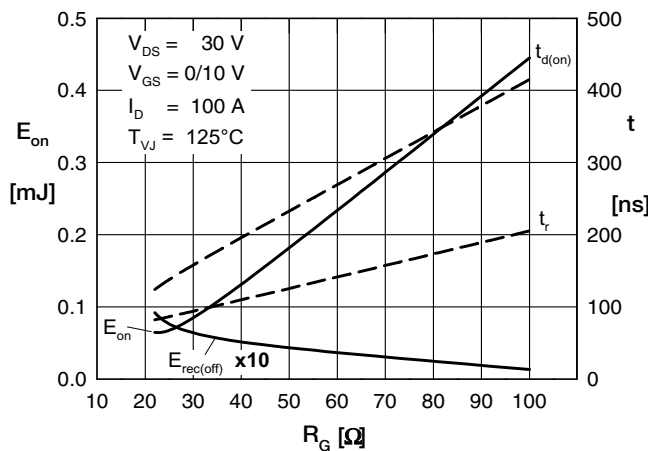


Fig. 11 Typ. turn-on energy and switching times versus gate resistor, inductive switching

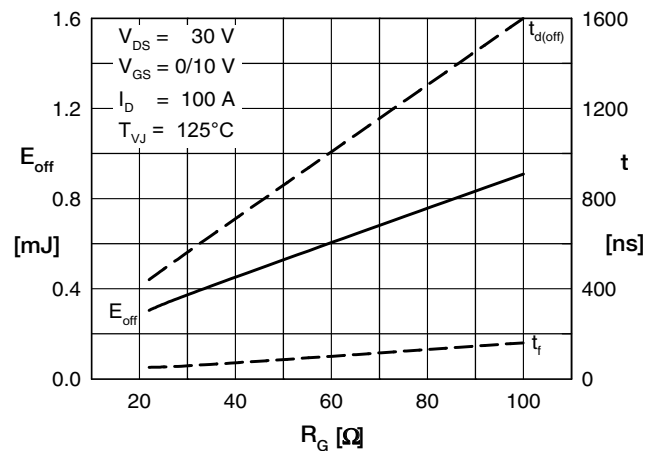


Fig. 12 Typ. turn-off energy and switching times versus gate resistor, inductive switching

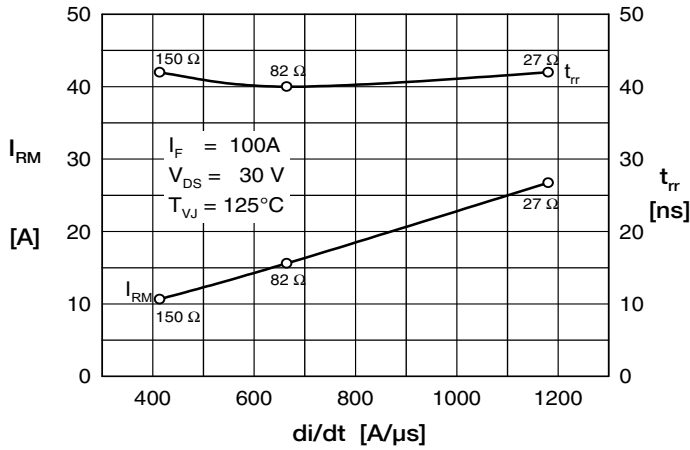


Fig. 13 Typ. reverse recovery characteristics

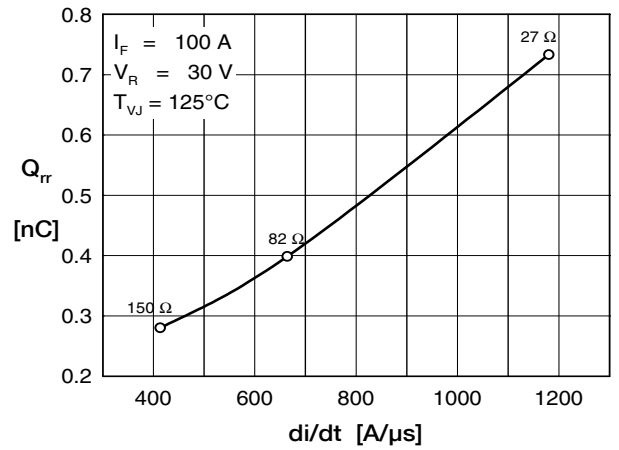


Fig. 14 Typ. reverse recovery characteristics

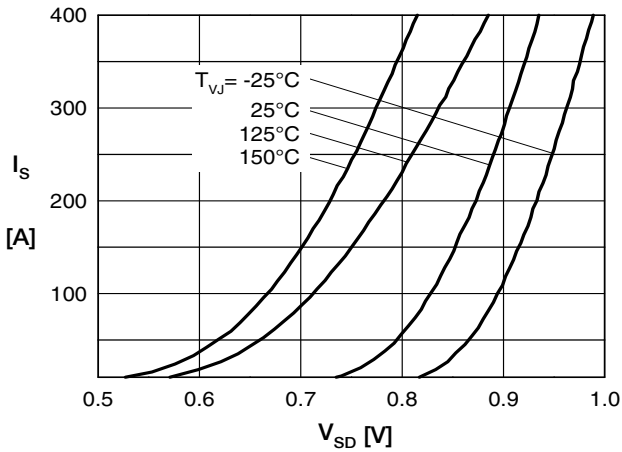


Fig.15 Source current I_s vs. source drain voltage V_{SD} (body diode) on die level

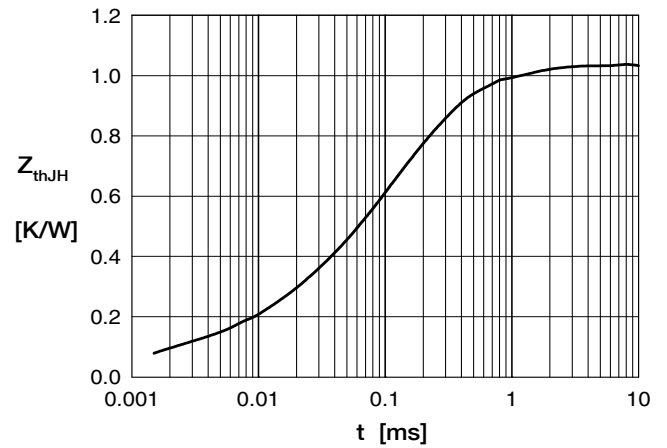


Fig. 16 Typ. thermal impedance junction to heatsink Z_{thJH} with heat transfer paste (IXYS test setup)

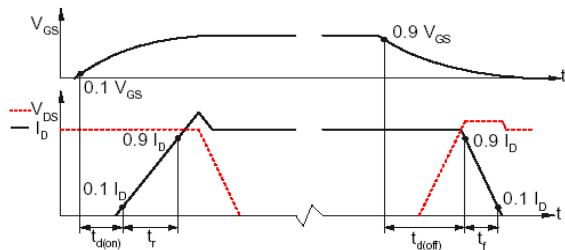


Fig. 17 Definition of switching times